

SYSTEM AND METHOD FOR GENERATING A SET OF TEST PATTERNS FOR AN OPTI- CAL PROXIMITY CORRECTION ALGO- RITHM

Abstract

A system and method of synthesizing layout patterns to test an optical proximity correction algorithm. The method comprises the steps of: embodying Walsh patterns in a set of Walsh pattern matrices; processing groups of matrices from the set of Walsh pattern matrices to form a set of test matrices; mapping the set of test matrices to a test pattern set.